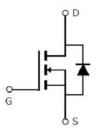


## **Main Product Characteristics:**

V <sub>DSS</sub>	60V
R <sub>DS</sub> (on)	8.8mΩ (typ.)
I <sub>D</sub>	60A





TO-252

Schematic Diagram

## **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



# **Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

# **Absolute Max Rating:**

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ①	60	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V ①	40	Α
I <sub>DM</sub>	Pulsed Drain Current ②	240	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation ③	85	W
V <sub>DS</sub>	Drain-Source Voltage	60	V
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C



# **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
Rejc	Junction-to-case ③	_	1.76	°C/W

# **Electrical Characterizes** @T<sub>A</sub>=25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	60	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
В	Static Drain-to-Source on-resistance	_	8.8	12	mΩ	V <sub>GS</sub> =10V,I <sub>D</sub> = 45A
R <sub>DS(on)</sub> Static Drain-to-Sou	Static Drain-to-Source on-resistance	_	12	17	mΩ	V <sub>GS</sub> =4.5V,I <sub>D</sub> = 45A
$V_{GS(th)}$	Gate threshold voltage	1	_	2.5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	1	μA	V <sub>DS</sub> = 60V,V <sub>GS</sub> = 0V
1	Cata ta Sauraa famuard la akaga	_	_	100	n 1	V <sub>GS</sub> =20V
I <sub>GSS</sub>	Gate-to-Source forward leakage	_	_	-100	nA	V <sub>GS</sub> = -20V
C <sub>iss</sub>	Input capacitance	_	2105	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	360	_	pF	V <sub>DS</sub> = 30V
Crss	Reverse transfer capacitance	_	13	_		f = 1MHz
Qg	Total gate charge	_	37	_		I <sub>D</sub> = 45A,
Q <sub>gs</sub>	Gate-to-Source charge	_	6.8	_	nC	V <sub>DS</sub> =30V,
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	_	5.9	_		V <sub>GS</sub> = 10V
t <sub>d(on)</sub>	Turn-on delay time	_	8	_		
t <sub>r</sub>	Rise time	_	2	_		V <sub>GS</sub> =10V, V <sub>DS</sub> =30V,
t <sub>d(off)</sub>	Turn-Off delay time	_	30	_	ns	$R_{GEN}$ =4.7 $\Omega$ , $I_D$ = 45A
t <sub>f</sub>	Fall time	_	4	_		

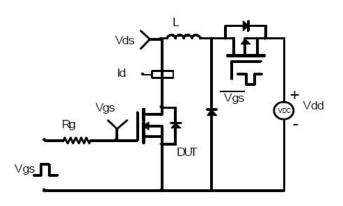
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			60	^	MOSFET symbol
ls	(Body Diode)	_	_	60	A	showing the
	Pulsed Source Current			240	^	integral reverse
I <sub>SM</sub>	(Body Diode)	_	_	240	A	p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	_	1.2	V	I <sub>S</sub> =30A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	_	38	_	ns	$T_J = 25$ °C, $I_F = I_S$ , $di/dt =$
Qrr	Reverse Recovery Charge	_	48		nC	100A/µs

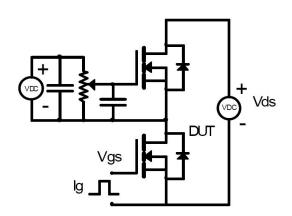


## **Test Circuits and Waveforms**

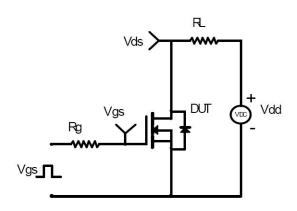
#### **EAS Test Circuit:**



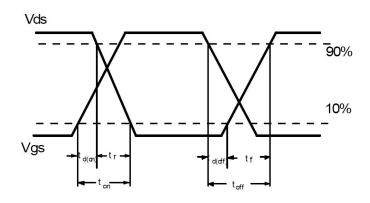
#### **Gate Charge Test Circuit:**



## **Switching Time Test Circuit:**



## **Switching Waveforms:**



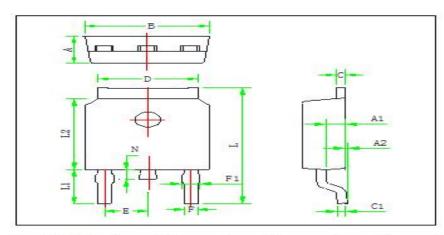
**Version: Preliminary** 

## Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- $\ \ \,$  The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.



# **Mechanical Data:**



Symbol	Min	Typ	Max		
A	2.20	2.30	2.40		
A1	0.91	1.01	1.11		
A2	0.05	0.15	0.25		
В	6.45	6.60	6.75		
C	0.45	0.50	0.58		
C1	0.45	0.50	0.58		
D	5.12	5.32	5.52		
E	2.286 TYP				
F	0.66 0.76 0.8				
F1	0.66	0.86	1.06		
L	9.60	9.90	10.20		
L1	2.6	2.8	3.0		
L2	5.95	6.10	6.25		
N	0.60	0.80	1.00		





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